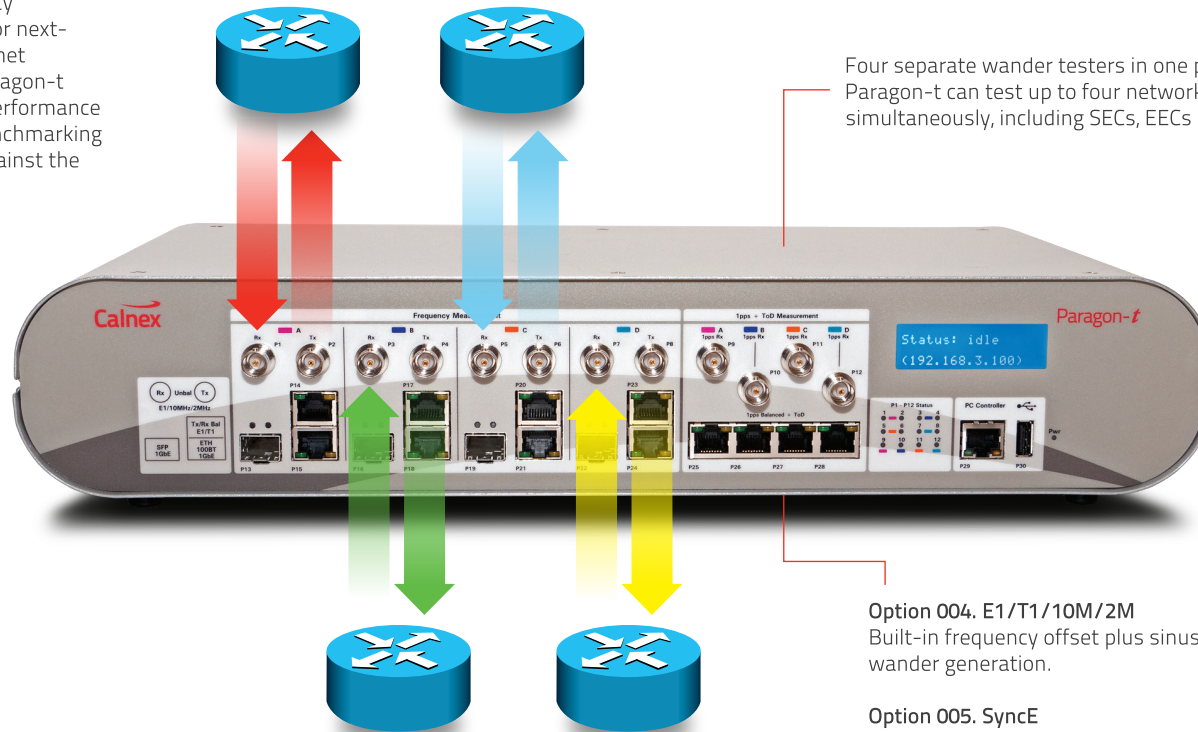


New Generation: Four wander testers in one.

For comprehensive Wander Tolerance testing, Paragon-t now comes with four independent transmit and measurement ports enabling you to test four separate devices simultaneously.

Whether for legacy synchronization or next-generation Ethernet deployments, Paragon-t proves wander performance at key rates – benchmarking and validating against the latest standards.



Four separate wander testers in one package: Paragon-t can test up to four network devices simultaneously, including SECs, EECs and BCs.

Option 004. E1/T1/10M/2M
Built-in frequency offset plus sinusoidal wander generation.

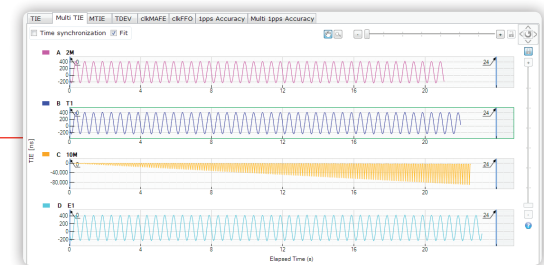
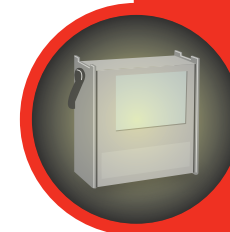
Option 005. SyncE
Built-in frequency offset plus sinusoidal wander generation.

Option 223. MTIE/TDEV
To ITU-T G.8262 and O.172/O.174

Invest in the future

If your current wander testers are coming to the end of their serviceable life, the Paragon-t is the ideal replacement. It covers all the wander test functions you need, adds the latest synchronisation technologies and, uniquely, gives you four independent wander interfaces to:

- save days of test time
- increase test coverage
- save on test equipment



Paragon-t's built-in CAT gives fast, clear insight into device performance with all your wander measurement results in one place. Plus, it provides easy pass/fail evaluation to G.8262/G.8261 standard or user masks.